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Ricardo Reis,Marcelo Soares
Lubaszewski,Jochen A.G. Jess

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Proceedings, International Test Conference 1997 ,1997 *Proceedings, International Test Conference 1996* ,1996 ITC is the World s largest premier technical conference on the testing and total quality of integrated electronics and the assenblies and systems that are based on them International Test Conference 1994 ,1994 **Testing for Small-Delay Defects in Nanoscale CMOS Integrated Circuits** Sandeep K. Goel,Krishnendu Chakrabarty,2017-12-19 Advances in design methods and process technologies have resulted in a continuous increase in the complexity of integrated circuits ICs However the increased complexity and nanometer size features of modern ICs make them susceptible to manufacturing defects as well as performance and quality issues Testing for Small Delay Defects in Nanoscale CMOS Integrated Circuits covers common problems in areas such as process variations power supply noise crosstalk resistive opens bridges and design for manufacturing DfM related rule violations The book also addresses testing for small delay defects SDDs which can cause immediate timing failures on both critical and non critical paths in the circuit Overviews semiconductor industry test challenges and the need for SDD testing including basic concepts and introductory material Describes algorithmic solutions incorporated in commercial tools from Mentor Graphics Reviews SDD testing based on alternative methods that explores new metrics top off ATPG and circuit topology based solutions Highlights the advantages and disadvantages of a diverse set of metrics and identifies scope for improvement Written from the triple viewpoint of university researchers EDA tool developers and chip designers and tool users this book is the first of its kind to address all aspects of SDD testing from such a diverse perspective The book is designed as a one stop reference for current industrial practices research challenges in the domain of SDD testing and recent developments in SDD solutions **Defect-Oriented Testing for Nano-Metric CMOS VLSI Circuits** Manoj Sachdev,José Pineda de Gyvez,2007-06-04 Defect oriented testing methods have come a long way from a mere interesting academic exercise to a hard industrial reality Many factors have contributed to its industrial acceptance Traditional approaches of testing modern integrated circuits have been found to be inadequate in terms of quality and economics of test In a globally competitive semiconductor market place overall product quality and economics have become very important objectives In addition electronic systems are becoming increasingly complex and demand components of the highest possible quality Testing in general and defect oriented testing in particular help in realizing these objectives For contemporary System on Chip SoC VLSI circuits testing is an activity associated with every level of integration However special emphasis is placed for wafer level test and final test Wafer level test consists primarily of dc or slow speed tests with current voltage checks per pin under most operating conditions and with test limits properly adjusted Basic digital tests are applied and in some cases low frequency tests to ensure analog RF functionality are exercised as well Final test consists of checking device functionality by exercising RF tests and by applying a comprehensive suite of digital test methods such as I delay fault testing DDQ stuck at testing low voltage testing etc This partitioning choice is actually application dependent

Integrated Circuit Test Engineering Ian A. Grout,2005-12-08 Taking a three pronged approach test engineering from traditional test design and manufacturing view points Integrated Circuit Test Engineering encapsulates the subject as it stands today After introductory background from basic testing rules to trends in technology the reader learns about fabrication processes a complete range of detailed tests and procedures how to design for testability fault simulation automatic test equipment and the economics of testing The text incudes Worked examples and exercises well organized references and bibliography An introduction to the use of various software and languages such as MATLAB Spice Verilog HDL and VHDL A series of experiments based on material downloaded from springeronline com showing how to construct a hardware test arrangement for MS Windows PCs This book is a practical tool for advanced undergraduate and graduate electronic engineering students a resource for their tutors and a guide for the practising electronic engineer **Efficient Branch and Bound Search with Application to Computer-Aided Design** Xinghao Chen,Michael L. Bushnell,2012-12-06 Branch and bound search has been known for a long time and has been widely used in solving a variety of problems in computer aided design CAD and many important optimization problems In many applications the classic branch and bound search methods perform duplications of computations or rely on the search decision trees which keep track of the branch and bound search processes In CAD and many other technical fields the computational cost of constructing branch and bound search decision trees in solving large scale problems is prohibitive and duplications of computations are intolerable Efficient branch and bound methods are needed to deal with today s computational challenges Efficient branch and bound methods must not duplicate computations Efficient Branch and Bound Search with Application to Computer Aided Design describes an efficient branch and bound method for logic justification which is fundamental to automatic test pattern generation ATPG redundancy identification logic synthesis minimization verification and other problems in CAD The method is called justification equivalence based on the observation that justification processes may share identical subsequent search decision sequences With justification equivalence duplication of computations is avoided in the dynamic branch and bound search process without using search decision trees Efficient Branch and Bound Search with Application to Computer Aided Design consists of two parts The first part containing the first three chapters provides the theoretical work The second part deals with applications particularly ATPG for sequential circuits This book is particularly useful to readers who are interested in the design and test of digital circuits **Defect Oriented Testing for CMOS Analog and Digital Circuits** Manoj Sachdev,2013-06-29 Defect oriented testing is expected to play a significant role in coming generations of technology Smaller feature sizes and larger die sizes will make ICs more sensitive to defects that can not be modeled by traditional fault modeling approaches Furthermore with increased level of integration an IC may contain diverse building blocks Such blocks include digital logic PLAs volatile and non volatile memories and analog interfaces For such diverse building blocks traditional fault modeling and test approaches will become increasingly inadequate Defect oriented testing methods have come a long way from a mere interesting academic exercise to a hard industrial reality Many factors have contributed to its industrial acceptance Traditional approaches of testing modern integrated circuits ICs have been found to be inadequate in terms of quality and economics of test In a globally competitive semiconductor market place overall product quality and economics have become very important objectives In addition electronic systems are becoming increasingly complex and demand components of highest possible quality Testing in general and defect oriented testing in particular help in realizing these objectives Defect Oriented Testing for CMOS Analog and Digital Circuits is the first book to provide a complete overview of the subject It is essential reading for all design and test professionals as well as researchers and students working in the field A strength of this book is its breadth Types of designs considered include analog and digital circuits programmable logic arrays and memories Having a fault model does not automatically provide a test Sometimes design for testability hardware is necessary Many design for testability ideas supported by experimental evidence are included from the Foreword by Vishwani D Agrawal *Introduction to IDDQ Testing* S. Chakravarty,Paul J. Thadikaran,2012-12-06 Testing techniques for VLSI circuits are undergoing many exciting changes The predominant method for testing digital circuits consists of applying a set of input stimuli to the IC and monitoring the logic levels at primary outputs If for one or more inputs there is a discrepancy between the observed output and the expected output then the IC is declared to be defective A new approach to testing digital circuits which has come to be known as IDDQ testing has been actively researched for the last fifteen years In IDDQ testing the steady state supply current rather than the logic levels at the primary outputs is monitored Years of research suggests that IDDQ testing can significantly improve the quality and reliability of fabricated circuits This has prompted many semiconductor manufacturers to adopt this testing technique among them Philips Semiconductors Ford Microelectronics Intel Texas Instruments LSI Logic Hewlett Packard SUN microsystems Alcatel and SGS Thomson This increase in the use of IDDQ testing should be of interest to three groups of individuals associated with the IC business Product Managers and Test Engineers CAD Tool Vendors and Circuit Designers Introduction to IDDQ Testing is designed to educate this community The authors have summarized in one volume the main findings of more than fifteen years of research in this area *Models in Hardware Testing* Hans-Joachim Wunderlich,2009-11-12 Model based testing is the most powerful technique for testing hardware and software systems Models in Hardware Testing describes the use of models at all the levels of hardware testing The relevant fault models for nanoscaled CMOS technology are introduced and their implications on fault simulation automatic test pattern generation fault diagnosis memory testing and power aware testing are discussed Models and the corresponding algorithms are considered with respect to the most recent state of the art and they are put into a historical context by a concluding chapter on the use of physical fault models in fault tolerance

High Quality Test Pattern Generation and Boolean Satisfiability Stephan Eggersglüß,Rolf Drechsler,2012-02-01 This book provides an overview of automatic test pattern generation ATPG and introduces novel techniques to complement classical

ATPG based on Boolean Satisfiability SAT A fast and highly fault efficient SAT based ATPG framework is presented which is also able to generate high quality delay tests such as robust path delay tests as well as tests with long propagation paths to detect small delay defects The aim of the techniques and methodologies presented in this book is to improve SAT based ATPG in order to make it applicable in industrial practice Readers will learn to improve the performance and robustness of the overall test generation process so that the ATPG algorithm reliably will generate test patterns for most targeted faults in acceptable run time to meet the high fault coverage demands of industry The techniques and improvements presented in this book provide the following advantages Provides a comprehensive introduction to test generation and Boolean Satisfiability SAT Describes a highly fault efficient SAT based ATPG framework Introduces circuit oriented SAT solving techniques which make use of structural information and are able to accelerate the search process significantly Provides SAT formulations for the prevalent delay faults models in addition to the classical stuck at fault model Includes an industrial perspective on the state of the art in the testing along with SAT two topics typically distinguished from each other Low-Power High-Resolution Analog to Digital Converters Amir Zjajo,José Pineda de Gyvez,2010-10-29 With the fast advancement of CMOS fabrication technology more and more signal processing functions are implemented in the digital domain for a lower cost lower power consumption higher yield and higher re configurability This has recently generated a great demand for low power low voltage A D converters that can be realized in a mainstream deep submicron CMOS technology However the discrepancies between lithography wavelengths and circuit feature sizes are increasing Lower power supply voltages significantly reduce noise margins and increase variations in process device and design parameters Consequently it is steadily more difficult to control the fabrication process precisely enough to maintain uniformity The inherent randomness of materials used in fabrication at nanoscopic scales means that performance will be increasingly variable not only from die to die but also within each individual die Parametric variability will be compounded by degradation in nanoscale integrated circuits resulting in instability of parameters over time eventually leading to the development of faults Process variation cannot be solved by improving manufacturing tolerances variability must be reduced by new device technology or managed by design in order for scaling to continue Similarly within die performance variation also imposes new challenges for test methods In an attempt to address these issues Low Power High Resolution Analog to Digital Converters specifically focus on i improving the power efficiency for the high speed and low spurious spectral A D conversion performance by exploring the potential of low voltage analog design and calibration techniques respectively and ii development of circuit techniques and algorithms to enhance testing and debugging potential to detect errors dynamically to isolate and confine faults and to recover errors continuously The feasibility of the described methods has been verified by measurements from the silicon prototypes fabricated in standard 180nm 90nm and 65nm CMOS technology *Information Technology* Ricardo Reis,2006-04-11 This book contains a selection of tutorials on hot topics in information technology which were presented at the IFIP World Computer Congress WCC2004 took place at the Centre de Congr s Pierre Baudis in Toulouse France from 22 to 27 August 2004 The 11 chapters included in the book were chosen from tutorials proposals submitted to WCC2004 These papers report on several important and state of the art topics on information technology such as Quality of Service in Information Networks Risk Driven Development of Security Critical Systems Using UMLsec Developing Portable Software Formal Reasoning About Systems Software and Hardware Using Functionals Predicates and Relations The Problematic of Distributed Systems Supervision Software Rejuvenation Modeling and Analysis Test and Design for Test of Mixed Signal Integrated Circuits Web Services Applications of Multi Agent Systems Discrete Event Simulation Human Centered Automation We hereby would like to thank IFIP and more specifically WCC2004 Tutorials Committee and the authors for their contribution We also would like to thank the congress organizers who have done a great job Ricardo Reis Editor QUALITY OF SERVICE IN INFORMATION NETWORKS Augusto Casaca IST INESC R Alves Redol 1000 029 Lisboa Portugal Abstract This article introduces the problems concerned with the provision of end end quality of service in IP networks which are the basis of information networks describes the existing solutions for that provision and presents some of the current research items on the subject Key words Information networks IP networks Integrated Services Differentiated Services Multiprotocol Label Switching UMTS **Tenth International Conference on VLSI Design** ,1997 *Embedded Processor-Based Self-Test* Dimitris Gizopoulos,A. Paschalis,Yervant Zorian,2013-03-09 Embedded Processor Based Self Test is a guide to self testing strategies for embedded processors Embedded processors are regularly used today in most System on Chips SoCs Testing of microprocessors and embedded processors has always been a challenge because most traditional testing techniques fail when applied to them This is due to the complex sequential structure of processor architectures which consists of high performance datapath units and sophisticated control logic for performance optimization Structured Design for Testability DfT and hardware based self testing techniques which usually have a non trivial impact on a circuit s performance size and power can not be applied without serious consideration and careful incorporation into the processor design Embedded Processor Based Self Test shows how the powerful embedded functionality that processors offer can be utilized as a self testing resource Through a discussion of different strategies the book emphasizes on the emerging area of Software Based Self Testing SBST SBST is based on the idea of execution of embedded software programs to perform self testing of the processor itself and its surrounding blocks in the SoC SBST is a low cost strategy in terms of overhead area speed power development effort and test application cost as it is applied using low cost low speed test equipment Embedded Processor Based Self Test can be used by designers DfT engineers test practitioners researchers and students working on digital testing and in particular processor and SoC test This book sets the framework for comparisons among different SBST methodologies by discussing key requirements It presents successful applications of SBST to a number of embedded processors of different complexities and instruction set architectures Microelectronics Packaging Handbook R.R.

Tummala,Eugene J. Rymaszewski,Alan G. Klopfenstein,2013-11-27 Electronics has become the largest industry surpassing agriculture auto and heavy metal industries It has become the industry of choice for a country to prosper already having given rise to the phenomenal prosperity of Japan Korea Singapore Hong Kong and Ireland among others At the current growth rate total worldwide semiconductor sales will reach 300B by the year 2000 The key electronic technologies responsible for the growth of the industry include semiconductors the packaging of semiconductors for systems use in auto telecom computer consumer aerospace and medical industries displays magnetic and optical storage as well as software and system technologies There has been a paradigm shift however in these technologies from mainframe and supercomputer applications at any cost to consumer applications at approximately one tenth the cost and size Personal computers are a good example going from 500IMIP when products were first introduced in 1981 to a projected IIMIP within 10 years Thin light portable user friendly and very low cost are therefore the attributes of tomorrow s computing and communications systems Electronic packaging is defined as interconnection powering cool ing and protecting semiconductor chips for reliable systems It is a key enabling technology achieving the requirements for reducing the size and cost at the system and product level

Fault Diagnosis of Analog Integrated Circuits Prithviraj Kabisatpathy,Alok Barua,Satyabroto Sinha,2006-01-13 System on Chip SOC having both digital and analog circuits has become increasingly prevalent in integrated circuit manufacturing industry Electronic tests are classified as digital analog and mixed signal Current methodologies for the testing of digital circuits are well developed In contrast methodologies for the testing of analog circuits remain relatively underdeveloped due to the complex nature of analog signals Compared to digital testing analog testing lags far behind in methodologies and tools and therefore demands substantial research and development effort Fault Diagnosis of Analog Integrated Circuits is a textbook for advanced undergraduate and graduate level students as well as practicing engineers The objective of this book is to study the testing and fault diagnosis of analog and analog part of mixed signal circuits A background in analog integrated circuit artificial neural network is desirable but not essential The text covers the testing and fault diagnosis of both bipolar and Metal Oxide Semiconductor MOS circuits Fault model of the devices in analog domain has been introduced in the text The test stimulus generations are also discussed in details Experimental verification of some state of the art techniques has also been presented in the book It also contains problems that can be used as quiz or homework This book enables the reader to test an analog circuit that is implemented either in bipolar or MOS technology Improving Product Reliability and Software Quality Mark A. Levin,Ted T. Kalal,Jonathan Rodin,2019-05-28 The authoritative guide to the effective design and production of reliable technology products revised and updated While most manufacturers have mastered the process of producing quality products product reliability software quality and software security has lagged behind The revised second edition of Improving Product Reliability and Software Quality offers a comprehensive and detailed guide to implementing a hardware reliability and software quality process for technology products The authors noted experts in the field provide useful tools forms and spreadsheets for executing an effective product reliability and software quality development process and explore proven software quality and product reliability concepts The authors discuss why so many companies fail after attempting to implement or improve their product reliability and software quality program They outline the critical steps for implementing a successful program Success hinges on establishing a reliability lab hiring the right people and implementing a reliability and software quality process that does the right things well and works well together Designed to be accessible the book contains a decision matrix for small medium and large companies Throughout the book the authors describe the hardware reliability and software quality process as well as the tools and techniques needed for putting it in place The concepts ideas and material presented are appropriate for any organization This updated second edition Contains new chapters on Software tools Software quality process and software security Expands the FMEA section to include software fault trees and software FMEAs Includes two new reliability tools to accelerate design maturity and reduce the risk of premature wearout Contains new material on preventative maintenance predictive maintenance and Prognostics and Health Management PHM to better manage repair cost and unscheduled downtime Presents updated information on reliability modeling and hiring reliability and software engineers Includes a comprehensive review of the reliability process from a multi disciplinary viewpoint including new material on uprating and counterfeit components Discusses aspects of competition key quality and reliability concepts and presents the tools for implementation Written for engineers managers and consultants lacking a background in product reliability and software quality theory and statistics the updated second edition of Improving Product Reliability and Software Quality explores all phases of the product life cycle

VLSI Testing Stanley Leonard Hurst,1998 Hurst an editor at the Microelectronics Journal analyzes common problems that electronics engineers and circuit designers encounter while testing integrated circuits and the systems in which they are used and explains a variety of solutions available for overcoming them in both digital and mixed circuits Among his topics are faults in digital circuits generating a digital test pattern signatures and self tests structured design for testability testing structured digital circuits and microprocessors and financial aspects of testing The self contained reference is also suitable as a textbook in a formal course on the subject Annotation copyrighted by Book News Inc Portland OR *Design of Systems on a Chip: Design and Test* Ricardo Reis,Marcelo Soares Lubaszewski,Jochen A.G. Jess,2007-05-06 This book is the second of two volumes addressing the design challenges associated with new generations of semiconductor technology The various chapters are compiled from tutorials presented at workshops in recent years by prominent authors from all over the world Technology productivity and quality are the main aspects under consideration to establish the major requirements for the design and test of upcoming systems on a chip

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